

## **Supporting information**

# Crystallography-Induced Correlations in Pore Ordering of Anodic Alumina Films

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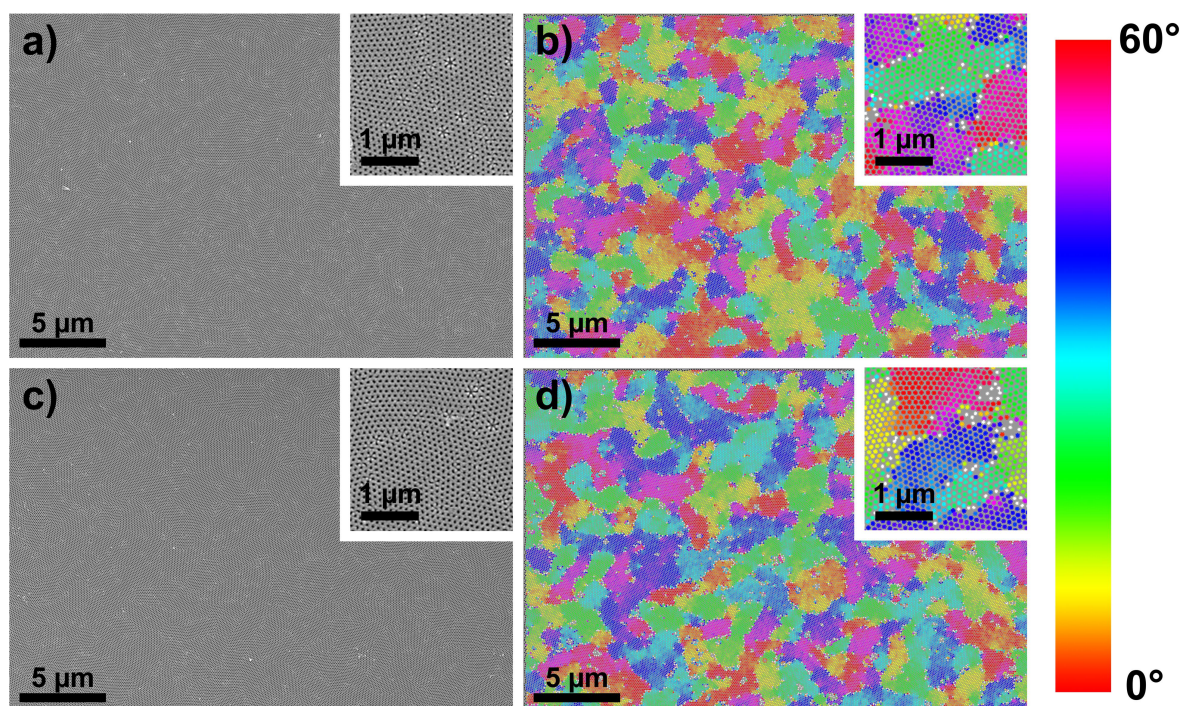
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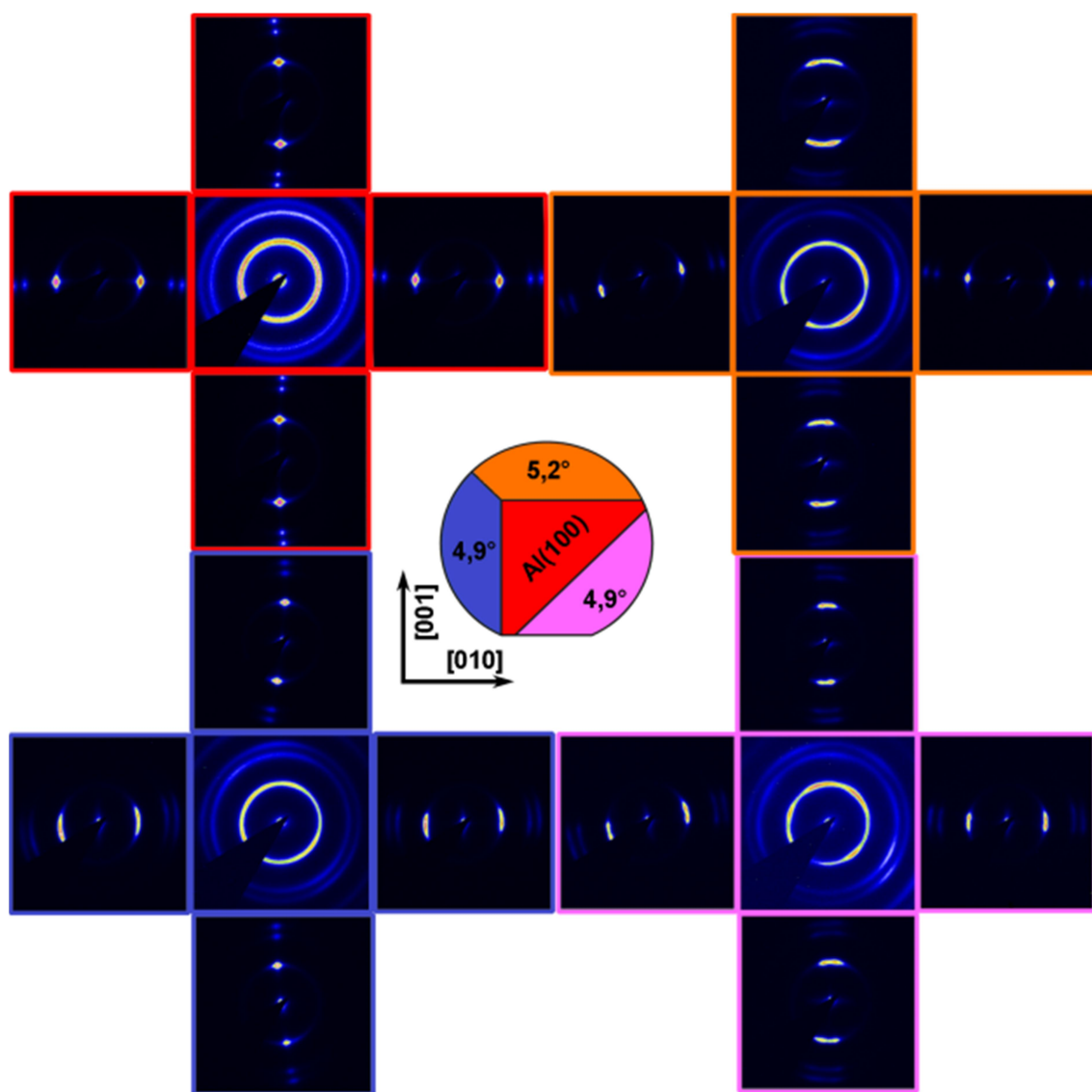
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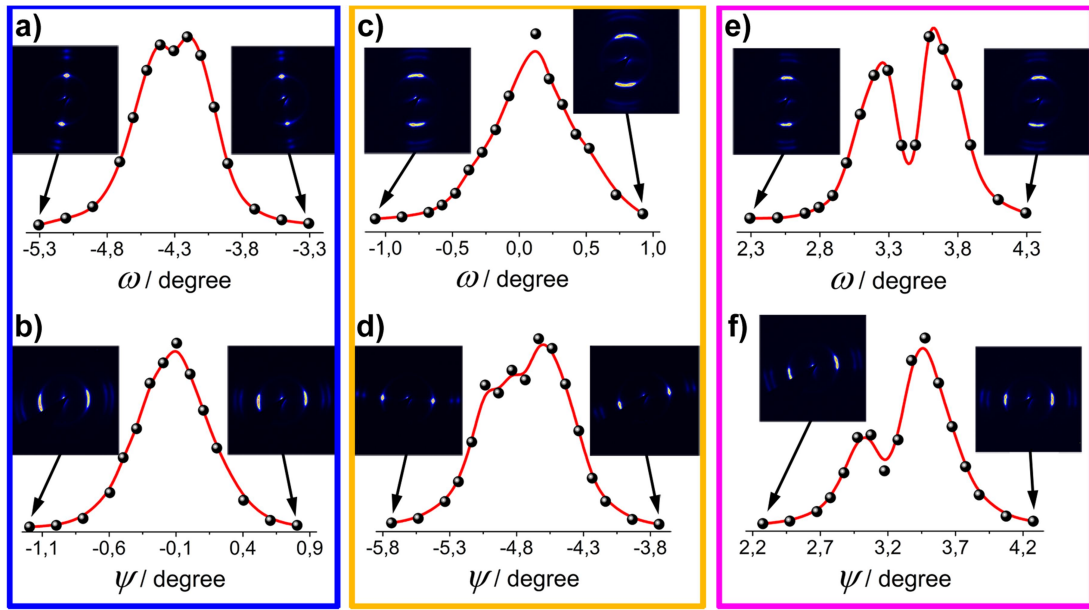
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**Figure S1.** Morphology of anodic alumina films. SEM images of the bottom side of AAO membranes, grown on the Al(100) substrate (a) and on the vicinal facet of single crystal #1 tilted by  $4.1^\circ$  (c). The barrier layer was removed by chemical etching before SEM analysis. Color-coded patterns corresponding to SEM images in panels (a) and (c) are shown in (b) and (d), respectively. The insets display high-magnification images for the each panel.



**Figure S2.** A sketch of aluminium single-crystal substrate with three vicinal zones (blue, orange and violet) tilted from the basal (100) plane by ca.  $5^\circ$  is shown in the centre. Small-angle diffraction patterns recorded at normal incidence of the X-ray beam to the AAO film surface (in the centre of each sets of diffraction patterns) and for rotation angles equal to  $\pm 1.0^\circ$  around the vertical (left and right patterns) and horizontal (top and bottom patterns) axes normal to the beam.



**Figure S3.** Rocking curves for 10 Bragg reflections, obtained during sample rotation around the vertical ( $\omega$ -scan) and horizontal ( $\psi$ -scan) axis orthogonal to the beam. The oxide film was prepared in 0.3 M oxalic acid at 40 V on the vicinal faces of single crystal #2: (a, b) tilting angle is  $4.9^\circ$  around [001] (marked by a blue color); (c, d) tilting angle is  $5.2^\circ$  around [010] (marked by an orange color); (e, f) tilting angle is  $4.9^\circ$  around [011] (marked by a violet color). All colors marks correspond with figure 1(d) in the text of manuscript. The diffraction patterns for extreme rotation angles are shown.